# E.J. Lattice Semiconductor Corporation - <u>LFE3-17EA-7FN484I Datasheet</u>



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#### Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Active
Number of LABs/CLBs	2125
Number of Logic Elements/Cells	17000
Total RAM Bits	716800
Number of I/O	222
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	484-BBGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe3-17ea-7fn484i

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# LatticeECP3 Family Data Sheet Introduction

#### February 2012

### **Features**

- Higher Logic Density for Increased System Integration
  - 17K to 149K LUTs
  - 116 to 586 I/Os
- Embedded SERDES
  - 150 Mbps to 3.2 Gbps for Generic 8b10b, 10-bit SERDES, and 8-bit SERDES modes
  - Data Rates 230 Mbps to 3.2 Gbps per channel for all other protocols
  - Up to 16 channels per device: PCI Express, SONET/SDH, Ethernet (1GbE, SGMII, XAUI), CPRI, SMPTE 3G and Serial RapidIO

### ■ sysDSP<sup>™</sup>

- Fully cascadable slice architecture
- 12 to 160 slices for high performance multiply and accumulate
- Powerful 54-bit ALU operations
- Time Division Multiplexing MAC Sharing
- Rounding and truncation
- Each slice supports
  - -Half 36x36, two 18x18 or four 9x9 multipliers
  - Advanced 18x36 MAC and 18x18 Multiply-
  - Multiply-Accumulate (MMAC) operations

### ■ Flexible Memory Resources

- Up to 6.85Mbits sysMEM<sup>™</sup> Embedded Block RAM (EBR)
- 36K to 303K bits distributed RAM
- sysCLOCK Analog PLLs and DLLs
   Two DLLs and up to ten PLLs per device
- Pre-Engineered Source Synchronous I/O
  - DDR registers in I/O cells

### Table 1-1. LatticeECP3™ Family Selection Guide

• Dedicated read/write levelling functionality

Data Sheet DS1021

- Dedicated gearing logic
- Source synchronous standards support
   ADC/DAC, 7:1 LVDS, XGMII
   Link Speed ADC/DAC devices
  - -High Speed ADC/DAC devices
- Dedicated DDR/DDR2/DDR3 memory with DQS support
- Optional Inter-Symbol Interference (ISI) correction on outputs
- Programmable sysl/O<sup>™</sup> Buffer Supports Wide Range of Interfaces
  - On-chip termination
  - Optional equalization filter on inputs
  - LVTTL and LVCMOS 33/25/18/15/12
  - SSTL 33/25/18/15 I, II
  - HSTL15 I and HSTL18 I, II
  - PCI and Differential HSTL, SSTL
  - LVDS, Bus-LVDS, LVPECL, RSDS, MLVDS

### Flexible Device Configuration

- Dedicated bank for configuration I/Os
- SPI boot flash interface
- Dual-boot images supported
- Slave SPI
- TransFR™ I/O for simple field updates
- Soft Error Detect embedded macro

### System Level Support

- IEEE 1149.1 and IEEE 1532 compliant
- Reveal Logic Analyzer
- ORCAstra FPGA configuration utility
- · On-chip oscillator for initialization & general use
- 1.2 V core power supply

Device	ECP3-17	ECP3-35	ECP3-70	ECP3-95	ECP3-150
LUTs (K)	17	33	67	92	149
sysMEM Blocks (18 Kbits)	38	72	240	240	372
Embedded Memory (Kbits)	700	1327	4420	4420	6850
Distributed RAM Bits (Kbits)	36	68	145	188	303
18 x 18 Multipliers	24	64	128	128	320
SERDES (Quad)	1	1	3	3	4
PLLs/DLLs	2/2	4/2	10/2	10 / 2	10/2
Packages and SERDES Channels	/ I/O Combinatio	ns		•	
328 csBGA (10 x 10 mm)	2/116				
256 ftBGA (17 x 17 mm)	4 / 133	4 / 133			
484 fpBGA (23 x 23 mm)	4 / 222	4 / 295	4 / 295	4 / 295	
672 fpBGA (27 x 27 mm)		4 / 310	8 / 380	8 / 380	8 / 380
1156 fpBGA (35 x 35 mm)			12 / 490	12 / 490	16 / 586

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### Figure 2-2. PFU Diagram



### Slice

Slice 0 through Slice 2 contain two LUT4s feeding two registers, whereas Slice 3 contains two LUT4s only. For PFUs, Slice 0 through Slice 2 can be configured as distributed memory, a capability not available in the PFF. Table 2-1 shows the capability of the slices in both PFF and PFU blocks along with the operation modes they enable. In addition, each PFU contains logic that allows the LUTs to be combined to perform functions such as LUT5, LUT6, LUT7 and LUT8. There is control logic to perform set/reset functions (programmable as synchronous/ asynchronous), clock select, chip-select and wider RAM/ROM functions.

Table 2-1.	Resources ar	nd Modes	Available	per Slice
	11000 di 000 di		/ 11 aa	

	PFU E	BLock	PFF Block		
Slice	Resources	Modes	Resources	Modes	
Slice 0	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM	2 LUT4s and 2 Registers	Logic, Ripple, ROM	
Slice 1	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM	2 LUT4s and 2 Registers	Logic, Ripple, ROM	
Slice 2	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM	2 LUT4s and 2 Registers	Logic, Ripple, ROM	
Slice 3	2 LUT4s	Logic, ROM	2 LUT4s	Logic, ROM	

Figure 2-3 shows an overview of the internal logic of the slice. The registers in the slice can be configured for positive/negative and edge triggered or level sensitive clocks.

Slices 0, 1 and 2 have 14 input signals: 13 signals from routing and one from the carry-chain (from the adjacent slice or PFU). There are seven outputs: six to routing and one to carry-chain (to the adjacent PFU). Slice 3 has 10 input signals from routing and four signals to routing. Table 2-2 lists the signals associated with Slice 0 to Slice 2.



### Figure 2-3. Slice Diagram



For Slices 0 and 1, memory control signals are generated from Slice 2 as follows: WCK is CLK WRE is from LSR

DI[3:2] for Slice 1 and DI[1:0] for Slice 0 data from Slice 2 WAD [A:D] is a 4-bit address from slice 2 LUT input

Table 2-2. Slice Signal Descriptions

Function	Туре	Signal Names	Description
Input	Data signal	A0, B0, C0, D0	Inputs to LUT4
Input	Data signal	A1, B1, C1, D1	Inputs to LUT4
Input	Multi-purpose	M0	Multipurpose Input
Input	Multi-purpose	M1	Multipurpose Input
Input	Control signal	CE	Clock Enable
Input	Control signal	LSR	Local Set/Reset
Input	Control signal	CLK	System Clock
Input	Inter-PFU signal	FC	Fast Carry-in <sup>1</sup>
Input	Inter-slice signal	FXA	Intermediate signal to generate LUT6 and LUT7
Input	Inter-slice signal	FXB	Intermediate signal to generate LUT6 and LUT7
Output	Data signals	F0, F1	LUT4 output register bypass signals
Output	Data signals	Q0, Q1	Register outputs
Output	Data signals	OFX0	Output of a LUT5 MUX
Output	Data signals	OFX1	Output of a LUT6, LUT7, LUT8 <sup>2</sup> MUX depending on the slice
Output	Inter-PFU signal	FCO	Slice 2 of each PFU is the fast carry chain output <sup>1</sup>

1. See Figure 2-3 for connection details.

2. Requires two PFUs.



### Modes of Operation

Each slice has up to four potential modes of operation: Logic, Ripple, RAM and ROM.

### Logic Mode

In this mode, the LUTs in each slice are configured as 4-input combinatorial lookup tables. A LUT4 can have 16 possible input combinations. Any four input logic functions can be generated by programming this lookup table. Since there are two LUT4s per slice, a LUT5 can be constructed within one slice. Larger look-up tables such as LUT6, LUT7 and LUT8 can be constructed by concatenating other slices. Note LUT8 requires more than four slices.

### **Ripple Mode**

Ripple mode supports the efficient implementation of small arithmetic functions. In ripple mode, the following functions can be implemented by each slice:

- Addition 2-bit
- Subtraction 2-bit
- Add/Subtract 2-bit using dynamic control
- Up counter 2-bit
- Down counter 2-bit
- Up/Down counter with asynchronous clear
- Up/Down counter with preload (sync)
- Ripple mode multiplier building block
- Multiplier support
- Comparator functions of A and B inputs
  - A greater-than-or-equal-to B
  - A not-equal-to B
  - A less-than-or-equal-to B

Ripple Mode includes an optional configuration that performs arithmetic using fast carry chain methods. In this configuration (also referred to as CCU2 mode) two additional signals, Carry Generate and Carry Propagate, are generated on a per slice basis to allow fast arithmetic functions to be constructed by concatenating Slices.

### RAM Mode

In this mode, a 16x4-bit distributed single port RAM (SPR) can be constructed using each LUT block in Slice 0 and Slice 1 as a 16x1-bit memory. Slice 2 is used to provide memory address and control signals. A 16x2-bit pseudo dual port RAM (PDPR) memory is created by using one Slice as the read-write port and the other companion slice as the read-only port.

LatticeECP3 devices support distributed memory initialization.

The Lattice design tools support the creation of a variety of different size memories. Where appropriate, the software will construct these using distributed memory primitives that represent the capabilities of the PFU. Table 2-3 shows the number of slices required to implement different distributed RAM primitives. For more information about using RAM in LatticeECP3 devices, please see TN1179, LatticeECP3 Memory Usage Guide.

#### Table 2-3. Number of Slices Required to Implement Distributed RAM

	SPR 16X4	PDPR 16X4
Number of slices	3	3

Note: SPR = Single Port RAM, PDPR = Pseudo Dual Port RAM



### Table 2-5. DLL Signals

Signal	I/O	Description
CLKI	I	Clock input from external pin or routing
CLKFB	I	DLL feed input from DLL output, clock net, routing or external pin
RSTN	I	Active low synchronous reset
ALUHOLD	I	Active high freezes the ALU
UDDCNTL	I	Synchronous enable signal (hold high for two cycles) from routing
CLKOP	0	The primary clock output
CLKOS	0	The secondary clock output with fine delay shift and/or division by 2 or by 4
LOCK	0	Active high phase lock indicator
INCI	I	Incremental indicator from another DLL via CIB.
GRAYI[5:0]	I	Gray-coded digital control bus from another DLL in time reference mode.
DIFF	0	Difference indicator when DCNTL is difference than the internal setting and update is needed.
INCO	0	Incremental indicator to other DLLs via CIB.
GRAYO[5:0]	0	Gray-coded digital control bus to other DLLs via CIB

LatticeECP3 devices have two general DLLs and four Slave Delay lines, two per DLL. The DLLs are in the lowest EBR row and located adjacent to the EBR. Each DLL replaces one EBR block. One Slave Delay line is placed adjacent to the DLL and the duplicate Slave Delay line (in Figure 2-6) for the DLL is placed in the I/O ring between Banks 6 and 7 and Banks 2 and 3.

The outputs from the DLL and Slave Delay lines are fed to the clock distribution network.

For more information, please see TN1178, LatticeECP3 sysCLOCK PLL/DLL Design and Usage Guide.

### Figure 2-6. Top-Level Block Diagram, High-Speed DLL and Slave Delay Line



\* This signal is not user accessible. It can only be used to feed the slave delay line.



This allows designers to use highly parallel implementations of DSP functions. Designers can optimize DSP performance vs. area by choosing appropriate levels of parallelism. Figure 2-23 compares the fully serial implementation to the mixed parallel and serial implementation.



### Figure 2-23. Comparison of General DSP and LatticeECP3 Approaches

### LatticeECP3 sysDSP Slice Architecture Features

The LatticeECP3 sysDSP Slice has been significantly enhanced to provide functions needed for advanced processing applications. These enhancements provide improved flexibility and resource utilization.

The LatticeECP3 sysDSP Slice supports many functions that include the following:

- Multiply (one 18 x 36, two 18 x 18 or four 9 x 9 Multiplies per Slice)
- Multiply (36 x 36 by cascading across two sysDSP slices)
- Multiply Accumulate (up to 18 x 36 Multipliers feeding an Accumulator that can have up to 54-bit resolution)
- Two Multiplies feeding one Accumulate per cycle for increased processing with lower latency (two 18 x 18 Multiplies feed into an accumulator that can accumulate up to 52 bits)
- Flexible saturation and rounding options to satisfy a diverse set of applications situations
- Flexible cascading across DSP slices
  - Minimizes fabric use for common DSP and ALU functions
  - Enables implementation of FIR Filter or similar structures using dedicated sysDSP slice resources only
  - Provides matching pipeline registers
  - Can be configured to continue cascading from one row of sysDSP slices to another for longer cascade chains
- Flexible and Powerful Arithmetic Logic Unit (ALU) Supports:
  - Dynamically selectable ALU OPCODE
  - Ternary arithmetic (addition/subtraction of three inputs)
  - Bit-wise two-input logic operations (AND, OR, NAND, NOR, XOR and XNOR)
  - Eight flexible and programmable ALU flags that can be used for multiple pattern detection scenarios, such



### MAC DSP Element

In this case, the two operands, AA and AB, are multiplied and the result is added with the previous accumulated value. This accumulated value is available at the output. The user can enable the input and pipeline registers, but the output register is always enabled. The output register is used to store the accumulated value. The ALU is configured as the accumulator in the sysDSP slice in the LatticeECP3 family can be initialized dynamically. A registered overflow signal is also available. The overflow conditions are provided later in this document. Figure 2-27 shows the MAC sysDSP element.

### Figure 2-27. MAC DSP Element





Two adjacent PIOs can be joined to provide a differential I/O pair (labeled as "T" and "C") as shown in Figure 2-32. The PAD Labels "T" and "C" distinguish the two PIOs. Approximately 50% of the PIO pairs on the left and right edges of the device can be configured as true LVDS outputs. All I/O pairs can operate as LVDS inputs.

### Table 2-11. PIO Signal List

Name	Туре	Description
INDD	Input Data	Register bypassed input. This is not the same port as INCK.
IPA, INA, IPB, INB	Input Data	Ports to core for input data
OPOSA, ONEGA <sup>1</sup> , OPOSB, ONEGB <sup>1</sup>	Output Data	Output signals from core. An exception is the ONEGB port, used for tristate logic at the DQS pad.
CE	PIO Control	Clock enables for input and output block flip-flops.
SCLK	PIO Control	System Clock (PCLK) for input and output/TS blocks. Connected from clock ISB.
LSR	PIO Control	Local Set/Reset
ECLK1, ECLK2	PIO Control	Edge clock sources. Entire PIO selects one of two sources using mux.
ECLKDQSR <sup>1</sup>	Read Control	From DQS_STROBE, shifted strobe for memory interfaces only.
DDRCLKPOL <sup>1</sup>	Read Control	Ensures transfer from DQS domain to SCLK domain.
DDRLAT <sup>1</sup>	Read Control	Used to guarantee INDDRX2 gearing by selectively enabling a D-Flip-Flop in dat- apath.
DEL[3:0]	Read Control	Dynamic input delay control bits.
INCK	To Clock Distribution and PLL	PIO treated as clock PIO, path to distribute to primary clocks and PLL.
TS	Tristate Data	Tristate signal from core (SDR)
DQCLK0 <sup>1</sup> , DQCLK1 <sup>1</sup>	Write Control	Two clocks edges, 90 degrees out of phase, used in output gearing.
DQSW <sup>2</sup>	Write Control	Used for output and tristate logic at DQS only.
DYNDEL[7:0]	Write Control	Shifting of write clocks for specific DQS group, using 6:0 each step is approxi- mately 25ps, 128 steps. Bit 7 is an invert (timing depends on input frequency). There is also a static control for this 8-bit setting, enabled with a memory cell.
DCNTL[6:0]	PIO Control	Original delay code from DDR DLL
DATAVALID <sup>1</sup>	Output Data	Status flag from DATAVALID logic, used to indicate when input data is captured in IOLOGIC and valid to core.
READ	For DQS_Strobe	Read signal for DDR memory interface
DQSI	For DQS_Strobe	Unshifted DQS strobe from input pad
PRMBDET	For DQS_Strobe	DQSI biased to go high when DQSI is tristate, goes to input logic block as well as core logic.
GSRN	Control from routing	Global Set/Reset

1. Signals available on left/right/top edges only.

2. Selected PIO.

### PIO

The PIO contains four blocks: an input register block, output register block, tristate register block and a control logic block. These blocks contain registers for operating in a variety of modes along with the necessary clock and selection logic.

### Input Register Block

The input register blocks for the PIOs, in the left, right and top edges, contain delay elements and registers that can be used to condition high-speed interface signals, such as DDR memory interfaces and source synchronous interfaces, before they are passed to the device core. Figure 2-33 shows the input register block for the left, right and top edges. The input register block for the bottom edge contains one element to register the input signal and no DDR registers. The following description applies to the input register block for PIOs in the left, right and top edges only.



Figure 2-40. SERDES/PCS Quads (LatticeECP3-150)



### Table 2-13. LatticeECP3 SERDES Standard Support

Standard	Data Rate (Mbps)	Number of General/Link Width	Encoding Style
PCI Express 1.1	2500	x1, x2, x4	8b10b
Gigabit Ethernet	1250, 2500	x1	8b10b
SGMII	1250	x1	8b10b
XAUI	3125	x4	8b10b
Serial RapidIO Type I, Serial RapidIO Type II, Serial RapidIO Type III	1250, 2500, 3125	x1, x4	8b10b
CPRI-1, CPRI-2, CPRI-3, CPRI-4	614.4, 1228.8, 2457.6, 3072.0	x1	8b10b
SD-SDI (259M, 344M)	143 <sup>1</sup> , 177 <sup>1</sup> , 270, 360, 540	x1	NRZI/Scrambled
HD-SDI (292M)	1483.5, 1485	x1	NRZI/Scrambled
3G-SDI (424M)	2967, 2970	x1	NRZI/Scrambled
SONET-STS-3 <sup>2</sup>	155.52	x1	N/A
SONET-STS-12 <sup>2</sup>	622.08	x1	N/A
SONET-STS-48 <sup>2</sup>	2488	x1	N/A

1. For slower rates, the SERDES are bypassed and CML signals are directly connected to the FPGA routing.

2. The SONET protocol is supported in 8-bit SERDES mode. See TN1176 Lattice ECP3 SERDES/PCS Usage Guide for more information.



### **Enhanced Configuration Options**

LatticeECP3 devices have enhanced configuration features such as: decryption support, TransFR™ I/O and dualboot image support.

### 1. TransFR (Transparent Field Reconfiguration)

TransFR I/O (TFR) is a unique Lattice technology that allows users to update their logic in the field without interrupting system operation using a single ispVM command. TransFR I/O allows I/O states to be frozen during device configuration. This allows the device to be field updated with a minimum of system disruption and downtime. See TN1087, Minimizing System Interruption During Configuration Using TransFR Technology for details.

### 2. Dual-Boot Image Support

Dual-boot images are supported for applications requiring reliable remote updates of configuration data for the system FPGA. After the system is running with a basic configuration, a new boot image can be downloaded remotely and stored in a separate location in the configuration storage device. Any time after the update the LatticeECP3 can be re-booted from this new configuration file. If there is a problem, such as corrupt data during download or incorrect version number with this new boot image, the LatticeECP3 device can revert back to the original backup golden configuration and try again. This all can be done without power cycling the system. For more information, please see TN1169, LatticeECP3 sysCONFIG Usage Guide.

### Soft Error Detect (SED) Support

LatticeECP3 devices have dedicated logic to perform Cycle Redundancy Code (CRC) checks. During configuration, the configuration data bitstream can be checked with the CRC logic block. In addition, the LatticeECP3 device can also be programmed to utilize a Soft Error Detect (SED) mode that checks for soft errors in configuration SRAM. The SED operation can be run in the background during user mode. If a soft error occurs, during user mode (normal operation) the device can be programmed to generate an error signal.

For further information on SED support, please see TN1184, LatticeECP3 Soft Error Detection (SED) Usage Guide.

### **External Resistor**

LatticeECP3 devices require a single external, 10 kOhm  $\pm$ 1% value between the XRES pin and ground. Device configuration will not be completed if this resistor is missing. There is no boundary scan register on the external resistor pad.

### **On-Chip Oscillator**

Every LatticeECP3 device has an internal CMOS oscillator which is used to derive a Master Clock (MCCLK) for configuration. The oscillator and the MCCLK run continuously and are available to user logic after configuration is completed. The software default value of the MCCLK is nominally 2.5 MHz. Table 2-16 lists all the available MCCLK frequencies. When a different Master Clock is selected during the design process, the following sequence takes place:

- 1. Device powers up with a nominal Master Clock frequency of 3.1 MHz.
- 2. During configuration, users select a different master clock frequency.
- 3. The Master Clock frequency changes to the selected frequency once the clock configuration bits are received.
- 4. If the user does not select a master clock frequency, then the configuration bitstream defaults to the MCCLK frequency of 2.5 MHz.

This internal 130 MHz +/- 15% CMOS oscillator is available to the user by routing it as an input clock to the clock tree. For further information on the use of this oscillator for configuration or user mode, please see TN1169, LatticeECP3 sysCONFIG Usage Guide.



### **DC Electrical Characteristics**

Symbol	Parameter	Condition	Min.	Тур.	Max.	Units
$I_{\rm IL}, I_{\rm IH}^{1, 4}$	Input or I/O Low Leakage	$0 \le V_{IN} \le (V_{CCIO} - 0.2 \text{ V})$	—	_	10	μΑ
I <sub>IH</sub> <sup>1, 3</sup>	Input or I/O High Leakage	$(V_{CCIO} - 0.2 \text{ V}) < V_{IN} \leq 3.6 \text{ V}$	—	_	150	μΑ
I <sub>PU</sub>	I/O Active Pull-up Current	$0 \le V_{IN} \le 0.7 V_{CCIO}$	-30	—	-210	μΑ
I <sub>PD</sub>	I/O Active Pull-down Current	$V_{IL}$ (MAX) $\leq V_{IN} \leq V_{CCIO}$	30	—	210	μΑ
I <sub>BHLS</sub>	Bus Hold Low Sustaining Current	$V_{IN} = V_{IL}$ (MAX)	30	_	—	μΑ
I <sub>BHHS</sub>	Bus Hold High Sustaining Current	$V_{IN} = 0.7 V_{CCIO}$	-30	—	—	μΑ
I <sub>BHLO</sub>	Bus Hold Low Overdrive Current	$0 \le V_{IN} \le V_{CCIO}$	_	—	210	μΑ
I <sub>BHHO</sub>	Bus Hold High Overdrive Current	$0 \le V_{IN} \le V_{CCIO}$	—	—	-210	μΑ
V <sub>BHT</sub>	Bus Hold Trip Points	$0 \le V_{IN} \le V_{IH}$ (MAX)	$V_{IL}$ (MAX)	—	$V_{IH}$ (MIN)	V
C1	I/O Capacitance <sup>2</sup>		_	5	8	pf
C2	Dedicated Input Capacitance <sup>2</sup>	$V_{CCIO} = 3.3 V, 2.5 V, 1.8 V, 1.5 V, 1.2 V, V_{CC} = 1.2 V, V_{IO} = 0 \text{ to } V_{IH} (MAX)$	_	5	7	pf

### **Over Recommended Operating Conditions**

1. Input or I/O leakage current is measured with the pin configured as an input or as an I/O with the output driver tri-stated. It is not measured with the output driver active. Bus maintenance circuits are disabled.

2. T<sub>A</sub> 25 °C, f = 1.0 MHz.

3. Applicable to general purpose I/Os in top and bottom banks. 4. When used as  $V_{REF}$  maximum leakage= 25  $\mu$ A.



### sysl/O Recommended Operating Conditions

		V <sub>CCIO</sub>		V <sub>REF</sub> (V)		
Standard	Min.	Тур.	Max.	Min.	Тур.	Max.
LVCMOS33 <sup>2</sup>	3.135	3.3	3.465	—	—	—
LVCMOS33D	3.135	3.3	3.465	—	—	—
LVCMOS25 <sup>2</sup>	2.375	2.5	2.625	—	—	—
LVCMOS18	1.71	1.8	1.89	—	—	—
LVCMOS15	1.425	1.5	1.575	—	—	—
LVCMOS12 <sup>2</sup>	1.14	1.2	1.26	—	—	—
LVTTL33 <sup>2</sup>	3.135	3.3	3.465	—	—	—
PCI33	3.135	3.3	3.465	—	—	—
SSTL15 <sup>3</sup>	1.43	1.5	1.57	0.68	0.75	0.9
SSTL18_I, II <sup>2</sup>	1.71	1.8	1.89	0.833	0.9	0.969
SSTL25_I, II <sup>2</sup>	2.375	2.5	2.625	1.15	1.25	1.35
SSTL33_I, II <sup>2</sup>	3.135	3.3	3.465	1.3	1.5	1.7
HSTL15_I <sup>2</sup>	1.425	1.5	1.575	0.68	0.75	0.9
HSTL18_I, II <sup>2</sup>	1.71	1.8	1.89	0.816	0.9	1.08
LVDS25 <sup>2</sup>	2.375	2.5	2.625	—	—	—
LVDS25E	2.375	2.5	2.625	—	—	—
MLVDS <sup>1</sup>	2.375	2.5	2.625	—	—	—
LVPECL33 <sup>1, 2</sup>	3.135	3.3	3.465	—	—	—
Mini LVDS	2.375	2.5	2.625	—	—	—
BLVDS25 <sup>1, 2</sup>	2.375	2.5	2.625	—	—	—
RSDS <sup>2</sup>	2.375	2.5	2.625	—	—	—
RSDSE <sup>1, 2</sup>	2.375	2.5	2.625	—	—	—
TRLVDS	3.14	3.3	3.47	—	—	—
PPLVDS	3.14/2.25	3.3/2.5	3.47/2.75	—	—	—
SSTL15D <sup>3</sup>	1.43	1.5	1.57	—	—	—
SSTL18D_I <sup>2, 3</sup> , II <sup>2, 3</sup>	1.71	1.8	1.89	—	—	—
SSTL25D_ I <sup>2</sup> , II <sup>2</sup>	2.375	2.5	2.625	—	—	—
SSTL33D_ I <sup>2</sup> , II <sup>2</sup>	3.135	3.3	3.465	—	—	—
HSTL15D_ I <sup>2</sup>	1.425	1.5	1.575		—	—
HSTL18D_ I <sup>2</sup> , II <sup>2</sup>	1.71	1.8	1.89	—	—	—

1. Inputs on chip. Outputs are implemented with the addition of external resistors.

2. For input voltage compatibility, see TN1177, LatticeECP3 sysIO Usage Guide.

3. VREF is required when using Differential SSTL to interface to DDR memory.



### LVPECL33

The LatticeECP3 devices support the differential LVPECL standard. This standard is emulated using complementary LVCMOS outputs in conjunction with a parallel resistor across the driver outputs. The LVPECL input standard is supported by the LVDS differential input buffer. The scheme shown in Figure 3-3 is one possible solution for point-to-point signals.

### Figure 3-3. Differential LVPECL33



### Table 3-3. LVPECL33 DC Conditions<sup>1</sup>

Parameter	Description	Typical	Units
V <sub>CCIO</sub>	Output Driver Supply (+/-5%)	3.30	V
Z <sub>OUT</sub>	Driver Impedance	10	Ω
R <sub>S</sub>	Driver Series Resistor (+/-1%)	93	Ω
R <sub>P</sub>	Driver Parallel Resistor (+/-1%)	196	Ω
R <sub>T</sub>	Receiver Termination (+/-1%)	100	Ω
V <sub>OH</sub>	Output High Voltage	2.05	V
V <sub>OL</sub>	Output Low Voltage	1.25	V
V <sub>OD</sub>	Output Differential Voltage	0.80	V
V <sub>CM</sub>	Output Common Mode Voltage	1.65	V
Z <sub>BACK</sub>	Back Impedance	100.5	Ω
I <sub>DC</sub>	DC Output Current	12.11	mA

### **Over Recommended Operating Conditions**

1. For input buffer, see LVDS table.



## LatticeECP3 External Switching Characteristics (Continued)<sup>1, 2, 3, 13</sup>

			-8		-	-7 -6		-6	
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
t <sub>HPLL</sub>	Clock to Data Hold - PIO Input Register	ECP3-70EA/95EA	0.7	—	0.7	_	0.8	—	ns
t <sub>SU_DELPLL</sub>	Clock to Data Setup - PIO Input Register with Data Input Delay ECP3-70EA/95		1.6	—	1.8	_	2.0	—	ns
t <sub>H_DELPLL</sub>	Clock to Data Hold - PIO Input Register with Input Data Delay	ECP3-70EA/95EA	0.0	—	0.0	—	0.0	—	ns
t <sub>COPLL</sub>	Clock to Output - PIO Output Register	ECP3-35EA	_	3.2	—	3.4	—	3.6	ns
t <sub>SUPLL</sub>	Clock to Data Setup - PIO Input Register	ECP3-35EA	0.6	_	0.7	—	0.8	—	ns
t <sub>HPLL</sub>	Clock to Data Hold - PIO Input Register	ECP3-35EA	0.3	—	0.3	—	0.4	-	ns
t <sub>SU_DELPLL</sub>	Clock to Data Setup - PIO Input Register with Data Input Delay	ECP3-35EA	1.6	_	1.7	_	1.8	_	ns
t <sub>H_DELPLL</sub>	Clock to Data Hold - PIO Input Register with Input Data Delay	ECP3-35EA	0.0	_	0.0	_	0.0	_	ns
t <sub>COPLL</sub>	Clock to Output - PIO Output Register	Clock to Output - PIO Output ECP3-17EA - 3.0 -		—	3.3	—	3.5	ns	
t <sub>SUPLL</sub>	Clock to Data Setup - PIO Input Register	ECP3-17EA	0.6	_	— 0.7		0.8	—	ns
t <sub>HPLL</sub>	Clock to Data Hold - PIO Input Register	ata Hold - PIO Input ECP3-17EA 0.3 — 0.3		0.3	_	0.4	—	ns	
t <sub>SU_DELPLL</sub>	Clock to Data Setup - PIO Input Register with Data Input Delay	ECP3-17EA	1.6	1.6 — 1.7		—	1.8	—	ns
t <sub>H_DELPLL</sub>	Clock to Data Hold - PIO Input Register with Input Data Delay	ECP3-17EA	0.0	_	0.0	_	0.0	—	ns
Generic DDR <sup>12</sup>									
Generic DDRX1 Inputs with Clock and Data (>10 Bits Wide) Centered at Pin (GDDRX1_RX.SCLK.Centered) Using PCLK Pin for Clock Input									
t <sub>SUGDDR</sub>	Data Setup Before CLK	All ECP3EA Devices	480	—	480	_	480		ps
t <sub>HOGDDR</sub>	Data Hold After CLK	All ECP3EA Devices	480	—	480	—	480		ps
f <sub>MAX_GDDR</sub>	DDRX1 Clock Frequency	All ECP3EA Devices	—	250	—	250	—	250	MHz
Generic DDRX1 In Clock Input	puts with Clock and Data (>10 Bits	Wide) Aligned at Pin	(GDDR)	(1_RX.SC	CLK.PLL	Aligned)	Using P	LLCLKIN	Pin for
Data Left, Right, and Top Sides and Clock Left and Right Sides									
t <sub>DVACLKGDDR</sub>	Data Setup Before CLK	All ECP3EA Devices	_	0.225		0.225		0.225	UI
t <sub>DVECLKGDDR</sub>	Data Hold After CLK	All ECP3EA Devices	0.775	—	0.775	—	0.775	_	UI
f <sub>MAX GDDR</sub>	DDRX1 Clock Frequency	All ECP3EA Devices	_	250	—	250	_	250	MHz
Generic DDRX1 In Clock Input	Generic DDRX1 Inputs with Clock and Data (>10 Bits Wide) Aligned at Pin (GDDRX1_RX.SCLK.Aligned) Using DLL - CLKIN Pin for Clock Input								
Data Left, Right ar	d Top Sides and Clock Left and R	ight Sides							
t <sub>DVACLKGDDR</sub>	Data Setup Before CLK	All ECP3EA Devices	_	0.225	—	0.225	—	0.225	UI
t <sub>DVECLKGDDR</sub>	Data Hold After CLK	All ECP3EA Devices	0.775	—	0.775	—	0.775		UI
f <sub>MAX GDDR</sub>	DDRX1 Clock Frequency	All ECP3EA Devices	_	250	—	250	_	250	MHz
Generic DDRX1 Inputs with Clock and Data (<10 Bits Wide) Centered at Pin (GDDRX1_RX.DQS.Centered) Using DQS Pin for Clock									
t <sub>SUGDDB</sub>	Data Setup After CLK	All ECP3EA Devices	535	_	535		535		ps
tHOGDDR	Data Hold After CLK	All ECP3EA Devices	535	—	535		535	_	ps
f <sub>MAX GDDB</sub>	DDRX1 Clock Frequency	All ECP3EA Devices	_	250	—	250	_	250	MHz
Generic DDRX1 In	puts with Clock and Data (<10bits	wide) Aligned at Pin (	GDDRX	1_RX.DQ	S.Aligne	d) Using	DQS Pin	for Cloc	k Input
Data and Clock Le	ft and Right Sides	· - · ·			-				-
t <sub>DVACI KGDDB</sub>	Data Setup Before CLK	All ECP3EA Devices	—	0.225	_	0.225		0.225	UI
STROLIGED									

### **Over Recommended Commercial Operating Conditions**







Note: Input data and address are registered at the positive edge of the clock and output data appears after the positive edge of the clock.



### LatticeECP3 Family Timing Adders<sup>1, 2, 3, 4, 5, 7</sup> (Continued)

Buffer Type	Description	-8	-7	-6	Units
RSDS25	RSDS, VCCIO = 2.5 V		-0.04	-0.01	ns
PPLVDS	Point-to-Point LVDS, True LVDS, VCCIO = 2.5 V or 3.3 V		-0.19	-0.16	ns
LVPECL33	LVPECL, Emulated, VCCIO = 3.3 V		0.76	0.86	ns
HSTL18_I	HSTL_18 class I 8mA drive, VCCIO = 1.8 V	1.20	1.34	1.47	ns
HSTL18_II	HSTL_18 class II, VCCIO = 1.8 V	0.89	1.00	1.11	ns
HSTL18D_I	Differential HSTL 18 class I 8 mA drive	1.20	1.34	1.47	ns
HSTL18D_II	Differential HSTL 18 class II	0.89	1.00	1.11	ns
HSTL15_I	HSTL_15 class I 4 mA drive, VCCIO = 1.5 V	1.67	1.83	1.99	ns
HSTL15D_I	Differential HSTL 15 class I 4 mA drive	1.67	1.83	1.99	ns
SSTL33_I	SSTL_3 class I, VCCIO = 3.3 V	1.12	1.17	1.21	ns
SSTL33_II	SSTL_3 class II, VCCIO = 3.3 V	1.08	1.12	1.15	ns
SSTL33D_I	Differential SSTL_3 class I	1.12	1.17	1.21	ns
SSTL33D_II	Differential SSTL_3 class II	1.08	1.12	1.15	ns
SSTL25_I	SSTL_2 class I 8 mA drive, VCCIO = 2.5 V	1.06	1.19	1.31	ns
SSTL25_II	SSTL_2 class II 16 mA drive, VCCIO = 2.5 V	1.04	1.17	1.31	ns
SSTL25D_I	Differential SSTL_2 class I 8 mA drive	1.06	1.19	1.31	ns
SSTL25D_II	Differential SSTL_2 class II 16 mA drive	1.04	1.17	1.31	ns
SSTL18_I	SSTL_1.8 class I, VCCIO = 1.8 V	0.70	0.84	0.97	ns
SSTL18_II	SSTL_1.8 class II 8 mA drive, VCCIO = 1.8 V	0.70	0.84	0.97	ns
SSTL18D_I	Differential SSTL_1.8 class I	0.70	0.84	0.97	ns
SSTL18D_II	Differential SSTL_1.8 class II 8 mA drive	0.70	0.84	0.97	ns
SSTL15	SSTL_1.5, VCCIO = 1.5 V	1.22	1.35	1.48	ns
SSTL15D	Differential SSTL_15	1.22	1.35	1.48	ns
LVTTL33_4mA	LVTTL 4 mA drive, VCCIO = 3.3V	0.25	0.24	0.23	ns
LVTTL33_8mA	LVTTL 8 mA drive, VCCIO = 3.3V	-0.06	-0.06	-0.07	ns
LVTTL33_12mA	LVTTL 12 mA drive, VCCIO = 3.3V	-0.01	-0.02	-0.02	ns
LVTTL33_16mA	LVTTL 16 mA drive, VCCIO = 3.3V	-0.07	-0.07	-0.08	ns
LVTTL33_20mA	LVTTL 20 mA drive, VCCIO = 3.3V	-0.12	-0.13	-0.14	ns
LVCMOS33_4mA	LVCMOS 3.3 4 mA drive, fast slew rate	0.25	0.24	0.23	ns
LVCMOS33_8mA	LVCMOS 3.3 8 mA drive, fast slew rate	-0.06	-0.06	-0.07	ns
LVCMOS33_12mA	LVCMOS 3.3 12 mA drive, fast slew rate	-0.01	-0.02	-0.02	ns
LVCMOS33_16mA	LVCMOS 3.3 16 mA drive, fast slew rate	-0.07	-0.07	-0.08	ns
LVCMOS33_20mA	LVCMOS 3.3 20 mA drive, fast slew rate	-0.12	-0.13	-0.14	ns
LVCMOS25_4mA	LVCMOS 2.5 4 mA drive, fast slew rate	0.12	0.10	0.09	ns
LVCMOS25_8mA	LVCMOS 2.5 8 mA drive, fast slew rate	-0.05	-0.06	-0.07	ns
LVCMOS25_12mA	LVCMOS 2.5 12 mA drive, fast slew rate	0.00	0.00	0.00	ns
LVCMOS25_16mA	LVCMOS 2.5 16 mA drive, fast slew rate	-0.12	-0.13	-0.14	ns
LVCMOS25_20mA	LVCMOS 2.5 20 mA drive, fast slew rate	-0.12	-0.13	-0.14	ns
LVCMOS18_4mA	LVCMOS 1.8 4 mA drive, fast slew rate	0.11	0.12	0.14	ns
LVCMOS18_8mA	LVCMOS 1.8 8 mA drive, fast slew rate	0.11	0.12	0.14	ns
LVCMOS18_12mA	LVCMOS 1.8 12 mA drive, fast slew rate	-0.04	-0.03	-0.03	ns
LVCMOS18_16mA	LVCMOS 1.8 16 mA drive, fast slew rate	-0.04	-0.03	-0.03	ns

### **Over Recommended Commercial Operating Conditions**



### **DLL** Timing

### **Over Recommended Operating Conditions**

Parameter	Description	Condition	Min.	Тур.	Max.	Units
f <sub>REF</sub>	Input reference clock frequency (on-chip or off-chip)		133	—	500	MHz
f <sub>FB</sub>	Feedback clock frequency (on-chip or off-chip)		133	—	500	MHz
f <sub>CLKOP</sub> 1	Output clock frequency, CLKOP		133	—	500	MHz
f <sub>CLKOS</sub> <sup>2</sup>	Output clock frequency, CLKOS		33.3	—	500	MHz
t <sub>PJIT</sub>	Output clock period jitter (clean input)			—	200	ps p-p
	Output clock duty cycle (at 50% levels, 50% duty	Edge Clock	40		60	%
t <sub>DUTY</sub>	off, time reference delay mode)	Primary Clock	30		70	%
	Output clock duty cycle (at 50% levels, arbitrary duty cycle input clock, 50% duty cycle circuit	Primary Clock < 250 MHz	45		55	%
t <sub>DUTYTRD</sub>		Primary Clock ≥ 250 MHz	30		70	%
	enabled, time reference delay mode)	Edge Clock	45		55	%
t <sub>DUTYCIR</sub>	Output clock duty cycle (at 50% levels, arbitrary duty cycle input clock, 50% duty cycle circuit enabled clock injection removal mode) with DLL	Primary Clock < 250 MHz	40		60	%
		Primary Clock ≥ 250 MHz	30		70	%
	cascading	Edge Clock	45		55	%
t <sub>SKEW</sub> <sup>3</sup>	Output clock to clock skew between two outputs with the same phase setting		_	—	100	ps
t <sub>PHASE</sub>	Phase error measured at device pads between off-chip reference clock and feedback clocks		_	—	+/-400	ps
t <sub>PWH</sub>	Input clock minimum pulse width high (at 80% level)		550	_	_	ps
t <sub>PWL</sub>	Input clock minimum pulse width low (at 20% level)		550	—	_	ps
t <sub>INSTB</sub>	Input clock period jitter			—	500	ps
t <sub>LOCK</sub>	DLL lock time		8	—	8200	cycles
t <sub>RSWD</sub>	Digital reset minimum pulse width (at 80% level)		3	—	—	ns
t <sub>DEL</sub>	Delay step size		27	45	70	ps
t <sub>RANGE1</sub>	Max. delay setting for single delay block (64 taps)		1.9	3.1	4.4	ns
t <sub>RANGE4</sub>	Max. delay setting for four chained delay blocks		7.6	12.4	17.6	ns

1. CLKOP runs at the same frequency as the input clock.

2. CLKOS minimum frequency is obtained with divide by 4.

3. This is intended to be a "path-matching" design guideline and is not a measurable specification.



### Table 3-7. Channel Output Jitter

Description	Frequency Min. Typ.		Max.	Units	
Deterministic	3.125 Gbps	— —		0.17	UI, p-p
Random	3.125 Gbps	—	—	0.25	UI, p-p
Total	3.125 Gbps	—	—	0.35	UI, p-p
Deterministic	2.5 Gbps	—	—	0.17	UI, p-p
Random	2.5 Gbps	—	—	0.20	UI, p-p
Total	2.5 Gbps	—	—	0.35	UI, p-p
Deterministic	1.25 Gbps	—	—	0.10	UI, p-p
Random	1.25 Gbps	—	—	0.22	UI, p-p
Total	1.25 Gbps	—	—	0.24	UI, p-p
Deterministic	622 Mbps	—	—	0.10	UI, p-p
Random	622 Mbps			0.20	UI, p-p
Total	622 Mbps			0.24	UI, p-p
Deterministic	250 Mbps	D Mbps — —		0.10	UI, p-p
Random	250 Mbps	bps —		0.18	UI, p-p
Total	250 Mbps	—	—	0.24	UI, p-p
Deterministic	150 Mbps	—	—	0.10	UI, p-p
Random	150 Mbps			0.18	UI, p-p
Total	150 Mbps			0.24	UI, p-p

Note: Values are measured with PRBS 2<sup>7</sup>-1, all channels operating, FPGA logic active, I/Os around SERDES pins quiet, reference clock @ 10X mode.



# Pin Information Summary (Cont.)

Pin Information		ECP3-95EA	ECP3-150EA				
Pin Type		484 fpBGA	672 fpBGA	1156 fpBGA	672 fpBGA	1156 fpBGA	
	Bank 0	42	60	86	60	94	
	Bank 1	36	48	78	48	86	
	Bank 2	24	34	36	34	58	
General Purpose	Bank 3	54	59	86	59	104	
	Bank 6	63	67	86	67	104	
	Bank 7	36	48	54	48	76	
	Bank 8	24	24	24	24	24	
	Bank 0	0	0	0	0	0	
	Bank 1	0	0	0	0	0	
	Bank 2	4	8	8	8	8	
General Purpose Inputs per	Bank 3	4	12	12	12	12	
Dank	Bank 6	4	12	12	12	12	
	Bank 7	4	8	8	8	8	
	Bank 8	0	0	0	0	0	
	Bank 0	0	0	0	0	0	
	Bank 1	0	0	0	0	0	
	Bank 2	0	0	0	0	0	
General Purpose Outputs per	Bank 3	0	0	0	0	0	
Dank	Bank 6	0	0	0	0	0	
	Bank 7	0	0	0	0	0	
	Bank 8	0	0	0	0	0	
Total Single-Ended User I/O		295	380	490	380	586	
VCC	16	32	32	32	32		
VCCAUX		8	12	16	12	16	
VTT		4	4	8	4	8	
VCCA	4	8	16	8	16		
VCCPLL		4	4	4	4	4	
	Bank 0	2	4	4	4	4	
	Bank 1	2	4	4	4	4	
	Bank 2	2	4	4	4	4	
VCCIO	Bank 3	2	4	4	4	4	
	Bank 6	2	4	4	4	4	
	Bank 7	2	4	4	4	4	
	Bank 8	2	2	2	2	2	
VCCJ		1	1	1	1	1	
TAP	4	4	4	4	4		
GND, GNDIO	98	139	233	139	233		
NC	0	0	238	0	116		
Reserved <sup>1</sup>	2	2	2	2	2		
SERDES	26	52	78	52	104		
Miscellaneous Pins	8	8	8	8	8		
Total Bonded Pins	484	672	1156	672	1156		



Date	Version	Section	Change Summary
			Updated Simplified Channel Block Diagram for SERDES/PCS Block diagram.
			Updated Device Configuration text section.
			Corrected software default value of MCCLK to be 2.5 MHz.
		DC and Switching Characteristics	Updated VCCOB Min/Max data in Recommended Operating Conditions table.
			Corrected footnote 2 in sysIO Recommended Operating Conditions table.
			Added added footnote 7 for t <sub>SKEW_PRIB</sub> to External Switching Characteristics table.
			Added 2-to-1 Gearing text section and table.
			Updated External Reference Clock Specification (refclkp/refclkn) table.
			LatticeECP3 sysCONFIG Port Timing Specifications - updated t <sub>DINIT</sub> information.
			Added sysCONFIG Port Timing waveform.
			Serial Input Data Specifications table, delete Typ data for $V_{RX-DIFF-S}$ .
			Added footnote 4 to sysCLOCK PLL Timing table for t <sub>PFD</sub> .
			Added SERDES/PCS Block Latency Breakdown table.
			External Reference Clock Specifications table, added footnote 4, add symbol name vREF-IN-DIFF.
			Added SERDES External Reference Clock Waveforms.
			Updated Serial Output Timing and Levels table.
			Pin-to-pin performance table, changed "typically 3% slower" to "typically slower".
			Updated timing information
			Updated SERDES minimum frequency.
			Added data to the following tables: External Switching Characteristics, Internal Switching Characteristics, Family Timing Adders, Maximum I/O Buffer Speed, DLL Timing, High Speed Data Transmitter, Channel Out- put Jitter, Typical Building Block Function Performance, Register-to- Register Performance, and Power Supply Requirements.
			Updated Serial Input Data Specifications table.
			Updated Transmit table, Serial Rapid I/O Type 2 Electrical and Timing Characteristics section.
		Pinout Information	Updated Signal Description tables.
			Updated Pin Information Summary tables and added footnote 1.
February 2009	01.0	_	Initial release.